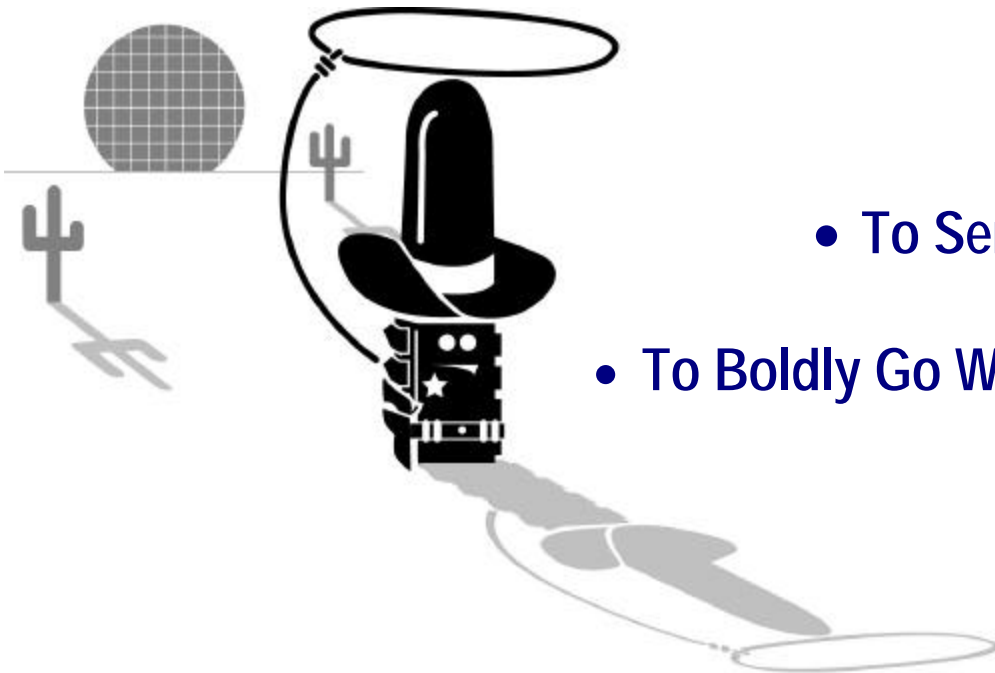


SOUTHWEST TEST WORKSHOP

- To Advance Wafer Testing Technology
- To Serve and Inform the Wafer Test Professional
- To Boldly Go Where No Other Workshop Has Gone Before

May 31 – June 3, 1998

San Diego, CA. USA



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THE COMMITTEE

Bill Mann – Rockwell

Mike Bonham – Cerprobe

Dave Unzicker – Intel

Rey Rincon – Texas Instruments

William Smith – Intel

Phil Seitzer – Lucent

Al Miller – Intel Mass.

Larry Gilg – MCC

What is a Test Workshop?

- **It's Not a Theoretical or Academic Conference**
- **Workshops are Informal and Casual**
- **Provides Practical Solutions to Real Problems**
- **Mixture of Vendor and User Presentations**
- **Open Discussions and Networking**
- **Opportunity for Informal Discussions**

INFORMAL INTERACTION

- **Long Breaks....Talk with a Stranger**
- **Three Hosted Cocktail Receptions**
- **Ample Social Activities**
 - **Barefoot Bar**
 - **After Dinner “Cordials”**
 - **Harbor Cruise**
 - **Miniature golf**
 - **Sea World**

TECHNICAL PROGRAM

- **Probe Tutorial**
- **“What the Users Really Want”**
- **Contact Resistance**
- **New Probe Technologies**
- **Probe Needle Cleaning**
- **RF Probing**

TECHNICAL PROGRAM

- **Parallel Probing**
- **Low Cost Probing**
- **Overall Accuracy**
- **Area Array Experiences**
- **Fine Pitch Issues**
- **Known Good Die**

PRIZES, PRIZES, AND MORE PRIZES

- **Best Technical Presentation**
- **Best Data Presented**
- **All Panel Members**
- **Best Questions Asked**
- **A Few Surprise Awards**
- **Tuesday Awards Banquet**
- **All Presenters on Wednesday**

TEST TECHNOLOGY PERIODICALS

- **International Test Conference Proceedings**
655 15th Street, N.W., Suite 300
Washington, D.C. 20005
- **Test Technology Technical Committee**
Newsletter
1474 Freeman Drive
Amissville, VA 20106
- **Journal of Electronic Testing**
Kiuwer Academic Publishers
101 Philip Drive
Norwell, MA 02061
- **Design and Test of Computers**
IEEE Computer Society
10662 Los Vagneros Circle
Los Alamitos, CA 90720-1314
- **Final Test Report**
Ikonix Corporation
P.O. Box 1938
Lafayette, CA 94549

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Southwest Test Workshop Technical Program

Sunday - May 31, 1998 - 2:00pm

Probe Tutorial

“Introduction to Gage R&R Studies”

Hank Scutoski and Chander Sekar
Cerprobe Corporation

“Introduction to Probing Technology”

Rod Schwartz
Integrated Technology Corporation {ITC}

Southwest Test Workshop Technical Program

Monday - June 1, 1998 - 8:30am

Contact Resistance

“Intro to Physics of Contact Resistance”

January Kister - Probe Technology Inc.

“Probe Needle Wear and Contact Resistance”

Jerry Broz - Advanced Probing Systems {APS}

“Multi-Tier Probe Cards and Contact Resistance”

John Strom - Applied Precision, Inc. {API}

Southwest Test Workshop Technical Program

Monday - June 1, 1998 - 10:30am

New Probe Technologies

“MicroStrip Beam Probes”

Lynn Saunders - MicroConnect, Inc.

“Thin Film Spring Arrays”

Don L. Smith - Xerox Research Center

“Application Specific Probe Needles”

Michelle Gesse - Advanced Probing Systems {APS}

Southwest Test Workshop Technical Program

Monday - June 1, 1998 - 1:00pm

Probe Needle Cleaning

“Probe Needle Cleaning”

Janusz Liberkowski - Tokyo Electron Massachusetts

“Innovative Probe Needle Cleaning Techniques”

James Anderson - Applied Precision, Inc. {API}

“Wet Cleaning”

Rod Schwartz - Integrated Technology Corporation

Southwest Test Workshop Technical Program

Monday - June 1, 1998 - 3:30pm

RF Probing

“Electrical Performance of PCB Materials”

Tom Strouth - GigaTest Labs

“Probe Card Design Using a Field Solver”

Eric Bogatin - Ansoft Corporation

“RF Membrane Probe Cards”

Ken Smith - Cascade Microteck, Inc.

“Reduced Probe Geometry”

Mike Chrasteky - Wentworth Labs

“RF Probe Test (1.9 GHz)”

Peter Luecking - Teradyne

Southwest Test Workshop Technical Program

Tuesday - June 2, 1998 - 8:00am

Overall Prober/Probe Card Accuracy

“Flexible Interface System”

Scott Williams - Cerprobe Corporation

“New Interface Paradigm: Direct Docking”

Rodger Sinsheimer and Doug Lefever - Xandex Corporation

“Overall Probe Accuracy at Elevated Temperature”

Phil Seitzer and Rick Langford - Lucent Technologies

“Overall Prober/Probe Card Accuracy”

Dai Dee Casavant - Electroglas

Southwest Test Workshop Technical Program

Tuesday - June 2, 1998 - 10:30am

Area Array Probing

“SEMATECH Overview”

Bob Nesbitt - SEMATECH

“Intro to Area Array Probing”

Fred Taber - IBM (NY)

“Area Array Probing”

Herve Deshayes - SGS Thompson

Southwest Test Workshop Technical Program

Wednesday - June 3, 1998 - 8:00am

Fine Pitch Probe

“Probing at 67 Micron Pitch”

Al Miller - Intel (Mass.)

“Fine Pitch Probe Card - 40 Micron Pitch ”

Kouichi Eguchi and Wolf Erben - Micronics Japan Co. {MJC}

“45 Micron Probe”

Toshi Ishi - Mitsubishi & Cerprobe Corporation

Southwest Test Workshop Technical Program

Wednesday - June 3, 1998 - 10:00am

Known Good Die

“Die Products Consortium”

Larry Gilg - MCC

“Overview of WLBI System Approaches”

Larry Gilg - MCC

“Known Good Die Standards”

Lori Hornback - Irvine Sensors Corporation

“More Power Scotty”

Dale Slaby - SGI/Cray Research